	Application No.	Applicant(s)	
Notice of Allowability	09/674,635	BALISKY, TODD ALAN	
	Examiner	Art Unit	· · · · · · · · · · · · · · · · · · ·
	Alexis Wachtel	1764	
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	ears on the cover sheet with the (OR REMAINS) CLOSED in this a or other appropriate communicati IGHTS. This application is subject	e correspondence address application. If not included ion will be mailed in due cours	e. THIS ne initiative
1. This communication is responsive to <u>amd proposed on 2-1</u>	<u>6-06</u> .		
2. The allowed claim(s) is/are 1-26.			
3. ☐ Acknowledgment is made of a claim for foreign priority un a) ☐ All b) ☐ Some* c) ☐ None of the:			
Certified copies of the priority documents have Certified copies of the priority documents have			
2. Certified copies of the priority documents have			
3. Copies of the certified copies of the priority doc	cuments have been received in th	is national stage application fro	om the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a reputential in the second section.	ly complying with the requirem	nents
4. A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give	itted. Note the attached EXAMINE reason(s) why the oath or decla	ER'S AMENDMENT or NOTICE aration is deficient.	E OF
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.			
(a) I including changes required by the Notice of Draftsperso		O-948) attached	
1) hereto or 2) to Paper No./Mail Date		,	
(b) including changes required by the attached Examiner's Paper No./Mail Date	Amendment / Comment or in the	Office action of	
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the	84(c)) should be written on the drawne header according to 37 CFR 1.12	wings in the front (not the back) 21(d).	of
6. DEPOSIT OF and/or INFORMATION about the depose attached Examiner's comment regarding REQUIREMENT F	sit of BIOLOGICAL MATERIAL FOR THE DEPOSIT OF BIOLOG	L must be submitted. Note th ICAL MATERIAL.	ne
Attachment(s)			
1. Notice of References Cited (PTO-892)		Patent Application (PTO-152))
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview Summa	ry (PTO-413),	
3. Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date	Paper No./Mail D 8), 7. ⊠ Examiner's Amen	idment/Comment	
Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. 💢 Examiner's Stater	ment of Reasons for Allowance	э
of biological Material	9.		

Detailed Action

Examiner's Amendment

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The instant Examiner's amendment was proposed by Keith Tackett on Feb 16, 2006 and overcomes any outstanding objections and renders the pending claims allowable.

The application has been amended as follows:

1. (Currently Amended) A chemical control system for controlling the chemistry of a chemical solution having predetermined chemical constituents in a plating system, the chemical control system comprising:

a mix container for containing a plating solution delivered from said mix container;

a precision delivery arrangement for delivering a precise-predetermined quantum of a predetermined constituent of the plating solution to a selectable combination of said mix container, said hold container, or both said mix container and said hold container;

a transfer pump for urging the plating solution to be transferred from said mix container to said hold container; and;

a source of deionized water in communication with said mix container; and

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a nitrogen gas source in communication with said source of deionized water for providing to said mix container a flow of nitrogen source gas to which has been added deionized water to form humidified nitrogen gas, the humidified nitrogen gas being humidified to a predetermined relative humidity with respect to the temperature of the plating solution in said mix container.

- 3. (Currently Amended) The chemical control system of claim 1, wherein said nitrogen gas source of deionized water comprises a column for containing the deionized water and releasing the humidified nitrogen gas, said column being in thermal communication with said mix tank container.
- 7. (Currently Amended) The chemical control system of claim 6, wherein said further nitrogen gas source comprises a further column for containing deionized water and releasing the humidified further nitrogen gas, said column being in thermal communication with said hold tank container.
- 12. (Currently Amended) The chemical control system of claim 11, wherein there is provided a further mix container, and said a precision delivery system is arranged to deliver a precise predetermined quantum of a predetermined constituent of the plating solution to each of said mix container and to said further mix container
- 14. (Currently Amended) The chemical control system of claim 11, wherein said source pump is configured to pump the predetermined constituent of the plating solution at a constituent flow rate <u>in a range</u> of approximately 100ml/min to 1.0l/min.
- 20. (Currently Amended) The chemical control system of claim 19, wherein said mix and hold pneumatic level sensors are arranged to provide a measurement along a

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predetermined length of the respectively associated ones of said mix and hold containers, respectively.

23. (Currently Amended) The chemical control system of claim 22, wherein said transfer pump is provided with a Teflen bellows made of Teflon polymer.

25. (Currently Amended) The chemical control system of claim 1, wherein there is further provided a chemical analyzer system that analyzes is adapted to analyze the plating solution in said mix container.

26. (Currently Amended) The chemical control system of claim 25, wherein said chemical analyzer system that analyzes the plating solution in said hold container

Allowable Subject Matter

2. Claim 1-26 are allowed.

Conclusion

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Alex Wachtel whose telephone number is 571-272-1455. The examiner can normally be reached on 10:30am to 6:30pm. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mr. Glenn Caldarola, can be reached at (571)-272-1444. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Cm

Gienn Caidarola Supervisory Patent Examiner

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